PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) Sheet 1 of 1 ATTORNEY DOCKET NO. SERIAL NO. 11 - 219 APPLICANT Jun OONISHI FILING DATE 1/29/04

U.S.PATENT DOCUMENTS						
Ref. Desig,	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
					·	
.,						

 	FOREIGN PATENT DOCUMENTS				Eng! Abst	English Abstract	
Ref. Desig,	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Yes	No
EO	ED	2003-28890	1/29/03	Japan		Х	
				· · · · · · · · · · · · · · · · · · ·		\	

	OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)					
Ref.	Examiner's					
Desig,	Initials					
		·				

EXAMINER: ATT	Date Considered:	8/18/05

EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if no in conformance and not considered. Include copy of this form with next communication to applicant.

REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
FB -	5,633,461	02/27/97	Kakizaki et al.	· · ·	

FOREIGN PATENT DOCUMENTS

TRANSLATION NO SUB CLASS YES DOCUMENT NUMBER DATE COUNTRY NAME CLASS Eng. Abstract \mathbf{X} 11/12/92 PCT WO 92/20096 \mathbf{X} 03/30/88 EP 0 261 555 Europe ЕI 08/08/96 DE 195 03 778 Germany

* Full English text is available in machine-translated form in JPO (Japanese Patent Office) English language web site at http://www1.ipdl.jpo.go.jp/PA1/cgi-bin/PA1INDEX.

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

	• • • • • • • • • • • • • • • • • • • •	
1		
	<u> </u>	
EXAMINER		DATE CONSIDERED
tw		8/18/05
D 1004 (F 2.6)	(e)	

Rev. 10/94 (Form 3/85)